

FORM PTO-1449  
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.: 5005.1057

SERIAL NO.: To Be Assigned

10/633222

## LIST OF PRIOR ART CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT(S): Ulrich KACZYNSKI

FILING DATE: Herewith

GROUP: To Be Assigned

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUBC CLASS	FILING DATE IF APPROPRIATE
<i>JS</i>	AA	20	03	00	53	0	3	7	Mar. 20, 2003	Blaesing-Bangert et al.	355	53	
	AB												
	AC												
	AD												
	AE												
	AF												
	AG												
	AH												
	AI												
	AJ												
	AK												

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB- CLASS S	TRANSLATION	
													YES	NO
<i>JS</i>	AL	1	0	1	4	0	1	74	Mar. 13, 2003	Germany	G12B	5/00	see U.S '037	
	AM													
	AN													
	AO													
	AP													

## OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>JS</i>	AQ	K.-D. Röth und K. Rinn, "Maskenmetrologie mit der LEICA LMS IPRO für die Halbleiter-Produktion", Leica Mikroskopie und Systeme GmbH, Wetzlar (Translation - see Application Text)
	AR	
	AS	

EXAMINER

*Johnson Jones*

DATE CONSIDERED

3/3/2005

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.